

Figure 1

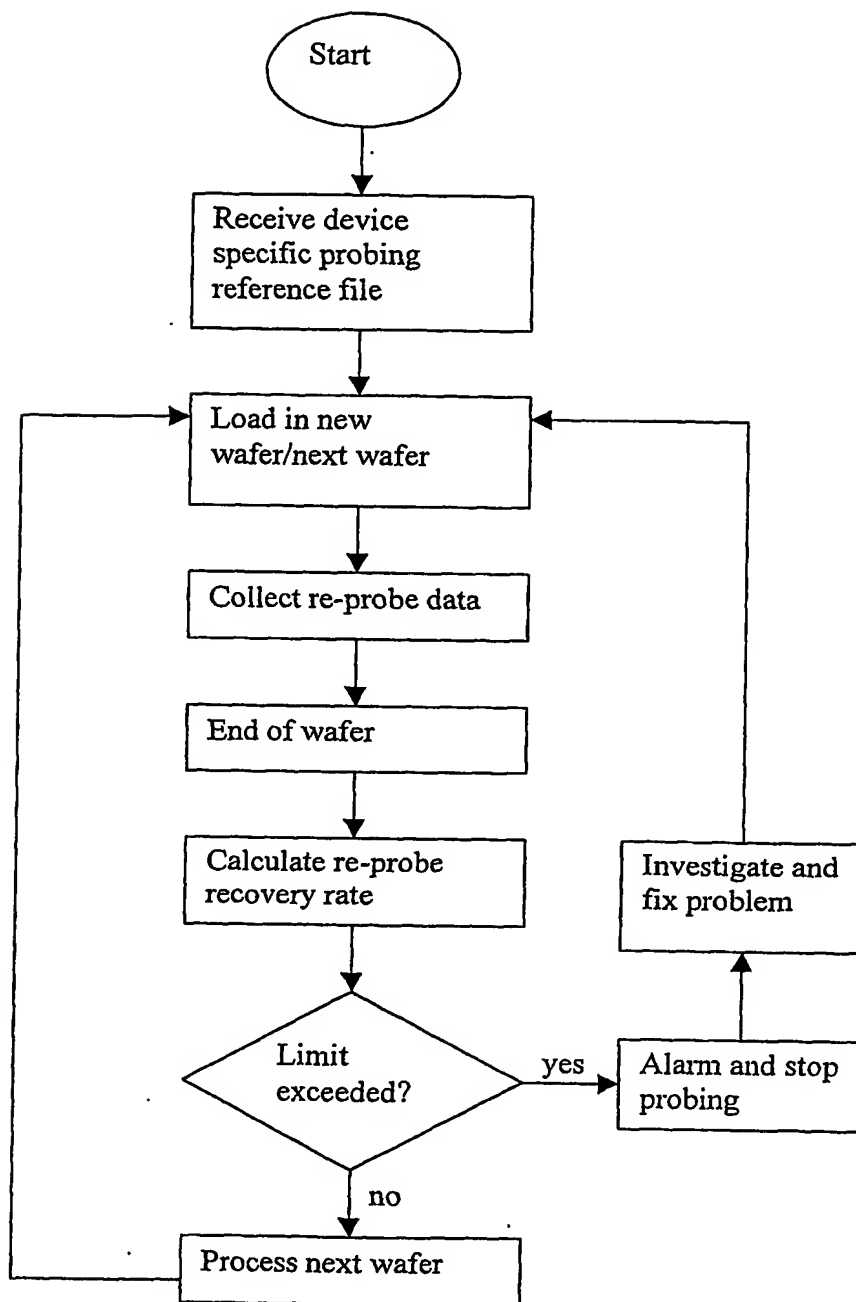
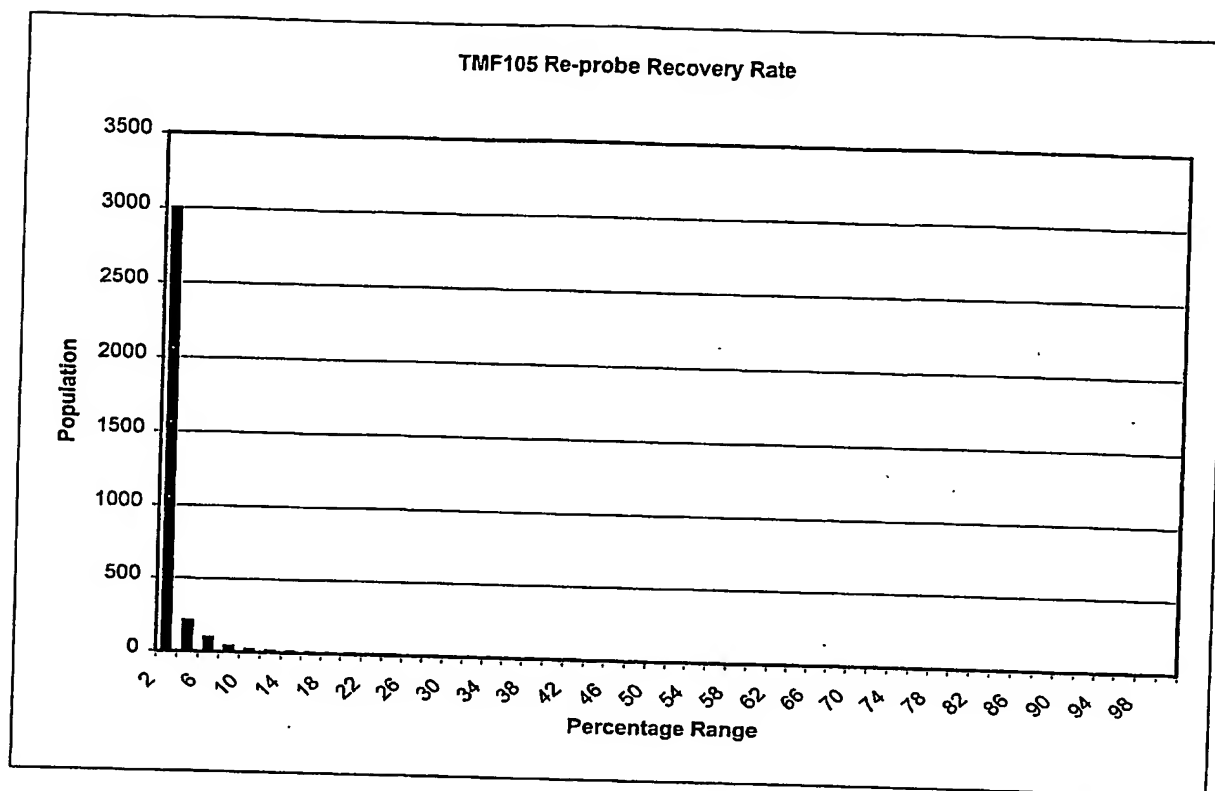


Figure 2

**Figure 3**

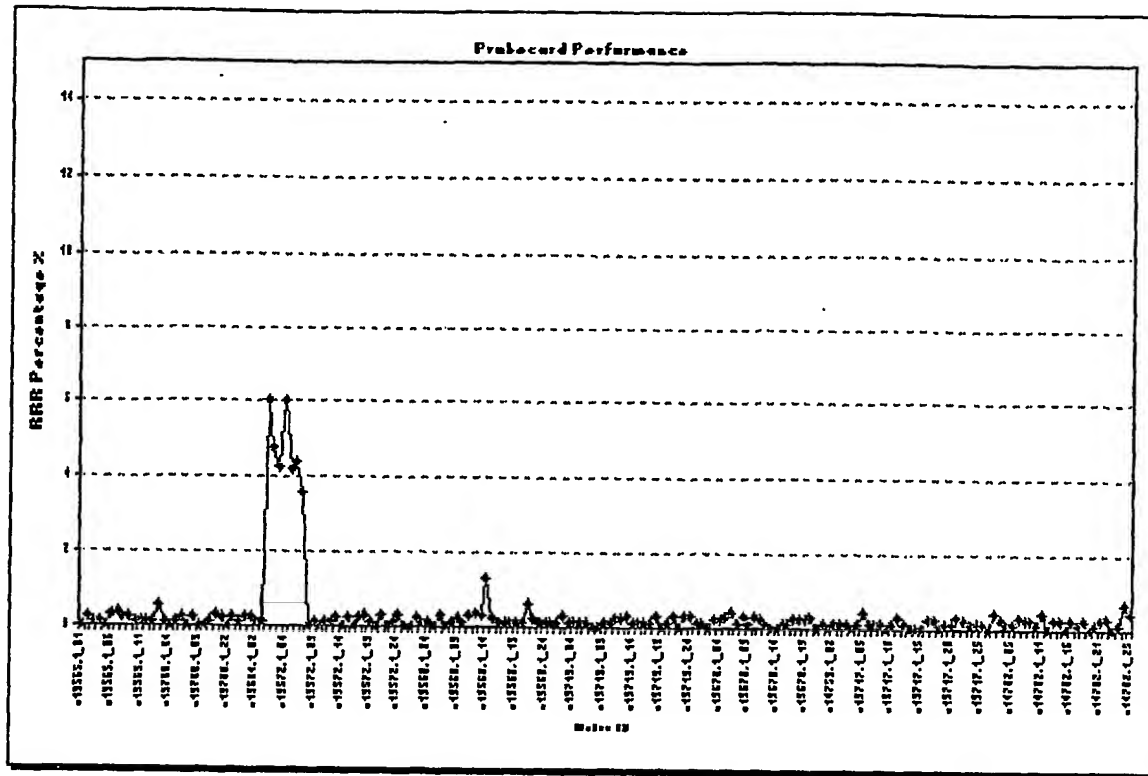


Figure 4

s16388.1\_06.20021001011407

Device :	TMF105_wr1	Tester :	D342X	Top	
Lot ID :	s16388.1	Board Num :	1	Touchdown :	1072
Wafer ID :	06	Probe Card :	3	PMU Measure :	5
Operator ID :	1058	Test Mode :	0	Indexing :	987
Timestamp :	20021001011407	Good Die :	898	Cleaning :	2
		RRR :	0.33	Recovery :	3
Bin to Bin Recovery			Top 10 CRC Fail Pins		
	Count	%		Count	%
IDD_FAIL(7) -> SCAN_SP_FAIL(16)	1	0.11	xo(73)	2	40.00
BIST_NOM_FAIL(8) -> GOOD(1)	1	0.11	pllo(11)	2	40.00
OPEN_FAIL(2) -> GOOD(1)	1	0.11	gclk1(2)	2	40.00
AMCLK(19) -> GOOD(1)	1	0.11	gclk(1)	2	40.00
FAIL -> GOOD	3	0.34			

Figure 5